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CAMS/LLNL Cs Sputter Ion Source Operating Conditions for C-Production

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Over the last several decades what was originally a General Ionex Corp. Model 846 high-intensity multi-sample negative ion source has been heavily modified to become what is now the Center for AMS at Lawrence Livermore National Laboratory's (CAMS/LLNL) general use Cs Sputter Negative Ion Sources. One of these CAMS/LLNL ion sources currently in operation at CAMS is used predominately for natural level ^{14}C measurements using the AMS system based around the CAMS HVEC FN accelerator. In order to optimize the operations of this ion source for such ^{14}C measurements, we have delved into the performance of the ion source under reasonable variation of various source parameters. The results obtain in these studies will be presented and discussed.

Student Submission

No

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